INTEGRATED CIRCUITS



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#### FEATURES

- 8-bit resolution
- Sampling rate up to 25 MHz
- 30 MHz input signal bandwidth (full scale)
- High signal-to-noise ratio over a large analog input frequency range (7.3 effective bits at 4.43 MHz full-scale input at  $f_{clk} = 25$  MHz)
- CMOS compatible digital inputs
- External reference voltage regulator
- Power dissipation only 53 mW (typical)
- Standby mode (only 1.2 mW typical)
- Low analog input capacitance, no buffer amplifier required
- No sample-and-hold circuit required.

### APPLICATIONS

Analog-to-digital conversion for:

- General purpose
- Hand-held equipment
- Mobile telecommunication
- Instrumentation
- Video.

#### **GENERAL DESCRIPTION**

The TDA8792 is a 8-bit analog-to-digital converter (ADC) for low-voltage, portable applications. It operates at 3.3 V and converts the analog input signal into 8-bit binary-coded digital words at a maximum sampling rate of 25 MHz. The output data is valid after a delay of 6 clock cycles.

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
V <sub>DDA</sub>	analog supply voltage		2.85	3.3	3.6	V
V <sub>DDD</sub>	digital supply voltage		2.70	3.3	3.6	V
V <sub>DDO</sub>	output stages supply voltage		2.5	3.3	3.6	V
I <sub>DDA</sub>	analog supply current		_	12	20	mA
I <sub>DDD</sub>	digital supply current		-	3	6	mA
IDDO	output stages supply current	$f_{clk}$ = 25 MHz; C <sub>L</sub> = 15 pF; ramp input	-	1	2	mA
INL	integral non-linearity	f <sub>clk</sub> = 25 MHz; ramp input	-	±0.4	±0.8	LSB
DNL	differential non-linearity	f <sub>clk</sub> = 25 MHz; ramp input	-	±0.3	±0.75	LSB
f <sub>clk(max)</sub>	maximum clock frequency		25	-	-	MHz
P <sub>tot</sub>	total power dissipation	$f_{clk} = 25 \text{ MHz}; C_L = 15 \text{ pF};$ ramp input	-	53	100	mW

### **ORDERING INFORMATION**

TYPE		PACKAGE	
NUMBER	NAME	DESCRIPTION	VERSION
TDA8792M	SSOP24	plastic shrink small outline package; 24 leads; body width 5.3 mm	SOT340-1

## QUICK REFERENCE DATA

TDA8792

## 3.3 V, 25 MHz 8-bit analog-to-digital converter (ADC)

### **BLOCK DIAGRAM**



### PINNING

SYMBOL	PIN	DESCRIPTION
STDBY	1	standby input
V <sub>DDD</sub>	2	digital supply voltage (+3.3 V)
V <sub>SSD2</sub>	3	digital ground 2
V <sub>SSA1</sub>	4	analog ground 1
VI	5	analog input voltage
V <sub>DDA</sub>	6	analog supply voltage (+3.3 V)
I <sub>bias</sub>	7	bias current input
V <sub>RT</sub>	8	reference voltage TOP input
V <sub>RM</sub>	9	reference voltage MIDDLE
V <sub>RB</sub>	10	reference voltage BOTTOM input
n.c.	11	not connected
V <sub>SSA2</sub>	12	analog ground 2
ŌĒ	13	output enable input (CMOS level input, active LOW)
D0	14	data output; bit 0 (LSB)
D1	15	data output; bit 1
D2	16	data output; bit 2
D3	17	data output; bit 3
D4	18	data output; bit 4
D5	19	data output; bit 5
D6	20	data output; bit 6
D7	21	data output; bit 7 (MSB)
V <sub>DDO</sub>	22	positive supply voltage for output stage (+3.3 V)
V <sub>SSO</sub>	23	output ground
CLK	24	clock input



### LIMITING VALUES

In accordance with the Absolute Maximum Rating System (IEC 134).

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
V <sub>DDA</sub>	analog supply voltage	note 1	-0.5	+5.0	V
V <sub>DDD</sub>	digital supply voltage	note 1	-0.5	+5.0	V
V <sub>DDO</sub>	output stages supply voltage	note 1	-0.5	+5.0	V
$\Delta V_{DD1}$	supply voltage differences between $\Delta V_{DD1} = V_{DDA} - V_{DDD}$		-0.3	+0.3	V
$\Delta V_{DD2}$	supply voltage differences between $\Delta V_{DD2} = V_{DDD} - V_{DDO}$		-1.0	+1.0	V
$\Delta V_{DD3}$	supply voltage differences between $\Delta V_{DD3} = V_{DDA} - V_{DDO}$		-1.0	+1.0	V
VI	input voltage	referenced to V <sub>SSA</sub>	-0.5	+5.0	V
V <sub>clk(p-p)</sub>	AC input voltage for switching (peak-to-peak value)	referenced to V <sub>SSD</sub>	-	V <sub>DDD</sub>	V
Io	output current		-	10	mA
T <sub>stg</sub>	storage temperature		-55	+150	°C
T <sub>amb</sub>	operating ambient temperature		-20	+75	°C
Tj	junction temperature		_	+125	°C

### Note

1. The supply voltages V<sub>DDA</sub>, V<sub>DDD</sub> and V<sub>DDO</sub> may have any value between –0.5 V and +5.0 V provided that the differences  $\Delta$ V<sub>DD1</sub>,  $\Delta$ V<sub>DD2</sub> and  $\Delta$ V<sub>DD3</sub> are respected.

### HANDLING

Inputs and outputs are protected against electrostatic discharges in normal handling. However, to be totally safe, it is desirable to take normal precautions appropriate to handling integrated circuits.

### THERMAL CHARACTERISTICS

SYMBOL	PARAMETER	VALUE	UNIT
R <sub>th j-a</sub>	thermal resistance from junction to ambient in free air	119	K/W

### CHARACTERISTICS

 $V_{DDA} = V_6 \text{ to } V_{4,12} = 2.85 \text{ to } 3.6 \text{ V}; V_{DDD} = V_2 \text{ to } V_3 \text{ and } V_1 = 2.7 \text{ to } 3.6 \text{ V}; V_{DDO} = V_{22} \text{ to } V_{23} = 2.5 \text{ to } 3.6 \text{ V}; \\ V_{SSA}, V_{SSD} \text{ and } V_{SSO} \text{ shorted together}; V_{DDA} \text{ to } V_{DDD} = -0.15 \text{ to } +0.15 \text{ V}; \\ f_{clk} = 25 \text{ MHz}; 50\% \text{ duty factor}; \\ V_{IL} = 0 \text{ V}; \\ V_{IH} = V_{DDD}; \\ C_L = 15 \text{ pF}; \\ T_{amb} = 0 \text{ to } +70 \text{ °C}; \\ typical values measured at \\ V_{DDA} = V_{DDD} = V_{DDO} = 3.3 \text{ V} \text{ and } \\ T_{amb} = 25 \text{ °C}; \\ unless otherwise specified.$ 

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
Supply			•		•	•
V <sub>DDA</sub>	analog supply voltage		2.85	3.3	3.6	V
V <sub>DDD</sub>	digital supply voltage		2.7	3.3	3.6	V
V <sub>DDO</sub>	output stages supply voltage		2.5	3.3	3.6	V
I <sub>DDA</sub>	analog supply current		-	12	20	mA
I <sub>DDD</sub>	digital supply current		_	3	6	mA
I <sub>DDO</sub>	output stages supply current	$C_L = 15 \text{ pF}; \text{ ramp input}$	-	1	2	mA
Inputs			ł			•
CLOCK INP	UT CLK (REFERENCED TO V <sub>SSD</sub> ); note 1					
VIL	LOW level input voltage		0	_	0.8	V
V <sub>IH</sub>	HIGH level input voltage		2.0	_	V <sub>DDD</sub>	V
IIL	LOW level input current	V <sub>clk</sub> = 0.4 V	-10	-	-	μA
I <sub>IH</sub>	HIGH level input current	V <sub>clk</sub> = 2.7 V	-	-	10	μA
CI	input capacitance		_	10	-	pF
INPUTS OE	and STDBY (referenced to $V_{SSD}$ ); see	Tables 2 and 3		•	•	
V <sub>IL</sub>	LOW level input voltage		0	_	0.8	V
V <sub>IH</sub>	HIGH level input voltage		2.0	_	V <sub>DDD</sub>	V
I <sub>IL</sub>	LOW level input current	$V_{IL} = 0.4 V$	-10	_	-	μA
I <sub>IH</sub>	HIGH level input current	V <sub>IH</sub> = 2.7 V	_	_	+10	μA
V <sub>I</sub> (ANALOG	B INPUT VOLTAGE REFERENCED TO $V_{\sf SSA}$ )					
IIL	LOW level input current	$V_{I} = 0 V$	-20	-	-	μA
I <sub>IH</sub>	HIGH level input current	V <sub>I</sub> = 1.5 V	_	-	+20	μA
ZI	input impedance	f <sub>i</sub> = 4.43 MHz	-	35	-	kΩ
CI	input capacitance	f <sub>i</sub> = 4.43 MHz	-	5	-	pF
Reference	e voltages for the resistor ladder; see Ta	able 1				
V <sub>RB</sub>	reference voltage BOTTOM		0	-	0.15	V
V <sub>RT</sub>	reference voltage TOP		1.4	_	1.6	V
V <sub>diff</sub>	differential reference voltage V <sub>RT</sub> - V <sub>RB</sub>		1.25	1.5	1.6	V
I <sub>ref</sub>	reference current		-	1.3	-	mA
R <sub>LAD</sub>	resistor ladder		-	1250	-	Ω
TC <sub>RLAD</sub>	temperature coefficient of the resistor ladder		_	1	-	Ω/Κ
			-			

## 3.3 V, 25 MHz 8-bit

analog-to-digital converter (ADC)

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
Outputs		1		1	1	1
DIGITAL OL	ITPUTS D7 TO D0 (REFERENCED TO V <sub>SSO</sub> )					
V <sub>OL</sub>	LOW level output voltage	I <sub>O</sub> = 1 mA	0	-	0.4	V
V <sub>OH</sub>	HIGH level output voltage	I <sub>O</sub> = -1 mA	V <sub>DDO</sub> - 0.4	-	V <sub>DDO</sub>	V
I <sub>OZ</sub>	output current in 3-state mode	$0.4 \text{ V} < \text{V}_{O} < \text{V}_{\text{DDO}}$	-10	-	+10	μA
Switching	characteristics				1	•
CLOCK INP	UT CLK (V <sub>DDA</sub> = 3.15 TO 3.45 V; V <sub>DDD</sub> = 3.	15 то 3.45 V); see Fig.3 an	d note 1			
f <sub>clk(max)</sub>	maximum clock frequency		25	-	_	MHz
f <sub>clk(min)</sub>	minimum clock frequency 0.5		0.5	-	-	MHz
t <sub>CPH</sub>	clock pulse width HIGH		16	-	_	ns
t <sub>CPL</sub>	clock pulse width LOW		16	-	-	ns
Analog si	gnal processing					•
LINEARITY						
INL	integral non-linearity	ramp input	_	±0.4	±0.8	LSB
DNL	differential non-linearity	ramp input	-	±0.3	±0.75	LSB
BANDWIDT	н (V <sub>DDA</sub> = 3.15 то 3.45 V; V <sub>DDD</sub> = 3.15 то 3	3.45 V); T <sub>AMB</sub> = 25 °C				
В	analog bandwidth	full-scale sine wave; note 2	20	30	-	MHz
		small signal at mid-scale; V <sub>i</sub> = $\pm 10$ LSB at code 128; note 2	_	35	_	MHz
t <sub>STLH</sub>	analog input settling time LOW-to-HIGH	full-scale square wave; Fig.5; note 3	-	8	12	ns
t <sub>STHL</sub>	analog input settling time HIGH-to-LOW	full-scale square wave; Fig.5; note 3	-	8	12	ns
HARMONIC	S					•
h <sub>1</sub>	fundamental harmonics (full scale)	f <sub>i</sub> = 4.43 MHz	-	-	0	dB
h <sub>all</sub>	harmonics (full scale); all components	f <sub>i</sub> = 4.43 MHz				
	second harmonics		-	-61	-	dB
	third harmonics		_	-61	-	dB
THD	total harmonic distortion	f <sub>i</sub> = 4.43 MHz	-	-58	-	dB
SIGNAL-TO	-NOISE RATIO; see Figs 6 and 11; note 4					
S/N	signal-to-noise ratio (full scale)	without harmonics; $f_{clk} = 25 \text{ MHz};$ $f_i = 4.43 \text{ MHz}$	-	46	-	dB

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SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
EFFECTIVE	BITS; see Figs 6 and 11; note 4					1
EB	effective bits	f <sub>clk</sub> = 25 MHz				
		f <sub>i</sub> = 2.0 MHz	-	7.4	_	bits
		f <sub>i</sub> = 4.43 MHz	_	7.3	-	bits
		f <sub>i</sub> = 7.5 MHz	_	7.2	-	bits
		$f_i = 10 \text{ MHz}$	_	7.0	-	bits
DIFFERENT	TAL GAIN; see note 5		i.		•	
G <sub>diff</sub>	differential gain	f <sub>clk</sub> = 25 MHz; PAL modulated ramp	-	1.5	-	%
DIFFERENT	TAL PHASE; see note 5		·	·	•	
Φdiff	differential phase	f <sub>clk</sub> = 25 MHz; PAL modulated ramp	-	0.5	-	deg
Timing (f			ł			
t <sub>ds</sub>	sampling delay time		-	-	2	ns
t <sub>h</sub>	output hold time		6	-	-	ns
t <sub>d</sub>	output delay time		8	13	25	ns
3-state ou	itput delay times; see Fig.4			•	•	
t <sub>dZH</sub>	enable HIGH		_	17	28	ns
t <sub>dZL</sub>	enable LOW		-	22	30	ns
t <sub>dHZ</sub>	disable HIGH		-	20	28	ns
t <sub>dLZ</sub>	disable LOW		_	22	30	ns
Standby I	node output delay times					
t <sub>dSTBLH</sub>	standby (LOW-to-HIGH transition)		-	-	200	ns
t <sub>dSTBHL</sub>	start-up (HIGH-to-LOW transition)		_	-	note 7	ns

#### Notes

- 1. In addition to a good layout of the digital and analog ground, it is recommended that the rise and fall times of the clock must not be less than 1 ns.
- 2. The analog bandwidth is defined as the maximum full-scale input sine wave frequency which can be applied to the device. No glitches greater than 8 LSBs are observed in the reconstructed signal neither is there any significant attenuation.
- 3. The analog input settling time is the minimum time required for the input signal to be stabilized after a sharp full-scale input (square-wave signal) in order to sample the signal and obtain correct output data.
- 4. Effective bits are obtained via a Fast Fourier Transform (FFT) treatment taking 8K acquisition points per equivalent fundamental period. The calculation takes into account all harmonics and noise up to half of the clock frequency (NYQUIST frequency). Conversion to signal-to-noise ratio: S/N = EB × 6.02 + 1.76 dB.
- 5. Measurement carried out using video analyser VM700A, where the video analog signal is reconstructed through a digital-to-analog converter.
- Output data acquisition: the output data is available after the maximum delay time of t<sub>d</sub>. In the event of 25 MHz clock operation, the hardware design must be taken into account the t<sub>d</sub> and t<sub>h</sub> limits with respect to the input characteristics of the acquisition circuit.
- 7. Maximum value standby mode start-up output delay time (HIGH-to-LOW transition):  $100 + \frac{7000}{f_{clk}(MHz)}$

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0755	M	BINARY OUTPUT BI						SITS			
STEP	V <sub>I(p-p) (V)</sub>	D7	D6	D5	D4	D3	D2	D1	D0		
Underflow	<0	0	0	0	0	0	0	0	0		
0	0	0	0	0	0	0	0	0	0		
1		0	0	0	0	0	0	0	1		
	-	•				•	•				
254		1	1	1	1	1	1	1	0		
255	1.5	1	1	1	1	1	1	1	1		
Overflow	>1.5	1	1	1	1	1	1	1	1		

### Table 1 Output coding and input voltage (typical values; referenced to V<sub>SSA</sub>)

### Table 2 Mode selection

OE

1

0

## Table 3 Standby selection

D7 TO D0	STDBY	D7 TO D0	I <sub>DDA</sub> + I <sub>DDD</sub> (typ.)
high impedance	1	LOW	0.4 mA
active; binary	0	active	15 mA









## TDA8792

## INTERNAL PIN CONFIGURATIONS



 $^{\sf V}{\sf SSA}$ 

MLD127

Fig.11 Bias current input.

### **APPLICATION INFORMATION**



For applications where the input signal must remain well centred around middle scale,  $V_{RM}$  must be decoupled and connected to analog input signal (pin 5) through a resistor. The values must be defined in accordance with the input signal frequency in order to avoid direct coupling into the ADC ladder (e.g. R = 5 k $\Omega$  and C = 100 nF).

(1)  $V_{RB}$ ,  $V_{RM}$  and  $V_{RT}$  are decoupled to  $V_{SSA}$ .

(2) Pin 11 should be connected to  $V_{SSA}$  in order to prevent noise influence.

Fig.12 Application diagram.

### PACKAGE OUTLINE



### SOLDERING SSOP

#### Introduction

There is no soldering method that is ideal for all IC packages. Wave soldering is often preferred when through-hole and surface mounted components are mixed on one printed-circuit board. However, wave soldering is not always suitable for surface mounted ICs, or for printed-circuits with high population densities. In these cases reflow soldering is often used.

This text gives a very brief insight to a complex technology. A more in-depth account of soldering ICs can be found in our *"IC Package Databook"* (order code 9398 652 90011).

#### **Reflow soldering**

Reflow soldering techniques are suitable for all SSOP packages.

Reflow soldering requires solder paste (a suspension of fine solder particles, flux and binding agent) to be applied to the printed-circuit board by screen printing, stencilling or pressure-syringe dispensing before package placement.

Several techniques exist for reflowing; for example, thermal conduction by heated belt. Dwell times vary between 50 and 300 seconds depending on heating method. Typical reflow temperatures range from 215 to 250 °C.

Preheating is necessary to dry the paste and evaporate the binding agent. Preheating duration: 45 minutes at 45 °C.

#### Wave soldering

Wave soldering is **not** recommended for SSOP packages. This is because of the likelihood of solder bridging due to closely-spaced leads and the possibility of incomplete solder penetration in multi-lead devices. If wave soldering cannot be avoided, the following conditions must be observed:

- A double-wave (a turbulent wave with high upward pressure followed by a smooth laminar wave) soldering technique should be used.
- The longitudinal axis of the package footprint must be parallel to the solder flow and must incorporate solder thieves at the downstream end.

Even with these conditions, only consider wave soldering SSOP packages that have a body width of 4.4 mm, that is SSOP16 (SOT369-1) or SSOP20 (SOT266-1).

During placement and before soldering, the package must be fixed with a droplet of adhesive. The adhesive can be applied by screen printing, pin transfer or syringe dispensing. The package can be soldered after the adhesive is cured.

Maximum permissible solder temperature is 260 °C, and maximum duration of package immersion in solder is 10 seconds, if cooled to less than 150 °C within 6 seconds. Typical dwell time is 4 seconds at 250 °C.

A mildly-activated flux will eliminate the need for removal of corrosive residues in most applications.

### **Repairing soldered joints**

Fix the component by first soldering two diagonallyopposite end leads. Use only a low voltage soldering iron (less than 24 V) applied to the flat part of the lead. Contact time must be limited to 10 seconds at up to 300 °C. When using a dedicated tool, all other leads can be soldered in one operation within 2 to 5 seconds at between 270 and 320 °C.

#### DEFINITIONS

Data sheet status					
Objective specification This data sheet contains target or goal specifications for product development.					
Preliminary specification	Preliminary specification This data sheet contains preliminary data; supplementary data may be published later.				
Product specification This data sheet contains final product specifications.					
Limiting values					
Limiting values given are in accordance with the Absolute Maximum Rating System (IEC 134). Stress above one or more of the limiting values may cause permanent damage to the device. These are stress ratings only and operation of the device at these or at any other conditions above those given in the Characteristics sections of the specification is not implied. Exposure to limiting values for extended periods may affect device reliability.					
Application information					

#### Application information

Where application information is given, it is advisory and does not form part of the specification.

#### LIFE SUPPORT APPLICATIONS

These products are not designed for use in life support appliances, devices, or systems where malfunction of these products can reasonably be expected to result in personal injury. Philips customers using or selling these products for use in such applications do so at their own risk and agree to fully indemnify Philips for any damages resulting from such improper use or sale.